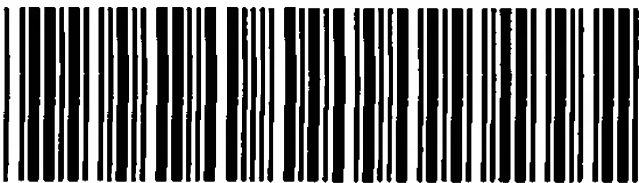


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/649,918	OKA ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Syed Zaidi	2616	

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Class	Subclass	Date	Examiner
370	328	10/15/2007	SZ

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	10/15/2007	SZ
Inventor : Oka et all	10/15/2007	SZ
IEEE Xplore Database( <a href="http://ieeexplore.ieee.org/Xplore/DynWel.jsp">http://ieeexplore.ieee.org/Xplore/DynWel.jsp</a> )	10/15/2007	SZ
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